

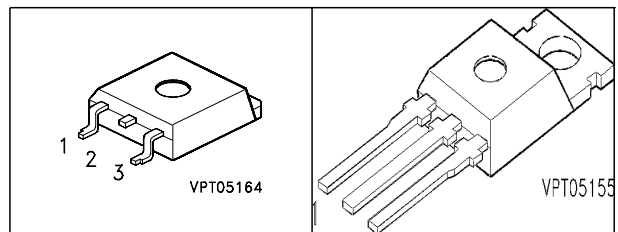
OptiMOS™ Power-Transistor

Features

- N-Channel
- Enhancement mode
- Avalanche rated
- Logic Level
- dv/dt rated
- 175°C operating temperature

Product Summary

Drain source voltage	V_{DS}	75	V
Drain-source on-state resistance	$R_{DS(on)}$	7.1	mΩ
Continuous drain current	I_D	80	A



Type	Package	Ordering Code
SPP80N08S2L-07	P-TO220-3-1	-
SPB80N08S2L-07	P-TO263-3-2	-

Pin 1	PIN 2/4	PIN 3
G	D	S

Maximum Ratings, at $T_j = 25\text{ °C}$, unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current $T_C = 25\text{ °C}$, ¹⁾ $T_C = 100\text{ °C}$	I_D	80 80	A
Pulsed drain current $T_C = 25\text{ °C}$	$I_{D\text{ puls}}$	320	
Avalanche energy, single pulse $I_D = 80\text{ A}$, $V_{DD} = 25\text{ V}$, $R_{GS} = 25\text{ Ω}$	E_{AS}	810	mJ
Avalanche energy, periodic limited by T_{jmax}	E_{AR}	35.7	
Reverse diode dv/dt $I_S = 80\text{ A}$, $V_{DS} = 60\text{ V}$, $di/dt = 200\text{ A/μs}$, $T_{jmax} = 175\text{ °C}$	dv/dt	6	kV/μs
Gate source voltage	V_{GS}	±20	V
Power dissipation $T_C = 25\text{ °C}$	P_{tot}	357	W
Operating and storage temperature	T_j, T_{stg}	-55...+175	°C
IEC climatic category; DIN IEC 68-1		55/175/56	

¹Current limited by bondwire; with an $R_{thJC} = 0.5\text{ K/W}$ the chip is able to carry $I_D = 132\text{ A}$

Thermal Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Characteristics					
Thermal resistance, junction - case	R_{thJC}	-	-	0.5	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	62	
SMD version, device on PCB: @ min. footprint @ 6 cm ² cooling area ¹⁾	R_{thJA}	-	-	62 40	

Electrical Characteristics, at $T_j = 25\text{ °C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Static Characteristics					
Drain-source breakdown voltage $V_{GS} = 0\text{ V}$, $I_D = 1\text{ mA}$	$V_{(BR)DSS}$	75	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 250\text{ }\mu\text{A}$	$V_{GS(th)}$	1.2	1.6	2	
Zero gate voltage drain current $V_{DS} = 75\text{ V}$, $V_{GS} = 0\text{ V}$, $T_j = 25\text{ °C}$ $V_{DS} = 75\text{ V}$, $V_{GS} = 0\text{ V}$, $T_j = 125\text{ °C}$	I_{DSS}	-	0.01 1	1 100	μA
Gate-source leakage current $V_{GS} = 20\text{ V}$, $V_{DS} = 0\text{ V}$	I_{GSS}	-	1	100	
Drain-source on-state resistance $V_{GS} = 4.5\text{ V}$, $I_D = 40\text{ A}$	$R_{DS(on)}$	-	tbd	9	m Ω
Drain-source on-state resistance $V_{GS} = 10\text{ V}$, $I_D = 40\text{ A}$	$R_{DS(on)}$	-	tbd	7.1	

¹Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air.

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Dynamic Characteristics

Transconductance $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$, $I_D = 80\text{ A}$	g_{fs}	tbd	tbd	-	S
Input capacitance $V_{GS} = 0\text{ V}$, $V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$	C_{iss}	-	tbd	tbd	pF
Output capacitance $V_{GS} = 0\text{ V}$, $V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$	C_{oss}	-	tbd	tbd	
Reverse transfer capacitance $V_{GS} = 0\text{ V}$, $V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$	C_{rss}	-	tbd	tbd	
Turn-on delay time $V_{DD} = 40\text{ V}$, $V_{GS} = 4.5\text{ V}$, $I_D = 80\text{ A}$, $R_G = 1.1\text{ }\Omega$	$t_{d(on)}$	-	tbd	tbd	ns
Rise time $V_{DD} = 40\text{ V}$, $V_{GS} = 4.5\text{ V}$, $I_D = 80\text{ A}$, $R_G = 1.1\text{ }\Omega$	t_r	-	tbd	tbd	
Turn-off delay time $V_{DD} = 40\text{ V}$, $V_{GS} = 4.5\text{ V}$, $I_D = 80\text{ A}$, $R_G = 1.1\text{ }\Omega$	$t_{d(off)}$	-	tbd	tbd	
Fall time $V_{DD} = 40\text{ V}$, $V_{GS} = 4.5\text{ V}$, $I_D = 80\text{ A}$, $R_G = 1.1\text{ }\Omega$	t_f	-	tbd	tbd	

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Gate Charge Characteristics					
Gate to source charge $V_{DD} = 60\text{ V}, I_D = 80\text{ A}$	Q_{gs}	-	tbd	tbd	nC
Gate to drain charge $V_{DD} = 60\text{ V}, I_D = 80\text{ A}$	Q_{gd}	-	tbd	tbd	
Gate charge total $V_{DD} = 60\text{ V}, I_D = 80\text{ A}, V_{GS} = 0\text{ to }10\text{ V}$	Q_g	-	tbd	tbd	
Gate plateau voltage $V_{DD} = 60\text{ V}, I_D = 80\text{ A}$	$V_{(plateau)}$	-	tbd	-	V

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Reverse Diode					
Inverse diode continuous forward current $T_C = 25\text{ }^\circ\text{C}$	I_S	-	-	80	A
Inverse diode direct current, pulsed $T_C = 25\text{ }^\circ\text{C}$	I_{SM}	-	-	320	
Inverse diode forward voltage $V_{GS} = 0\text{ V}, I_F = 80\text{ A}$	V_{SD}	-	0.9	1.3	V
Reverse recovery time $V_R = 40\text{ V}, I_F = I_S, di_F/dt = 100\text{ A}/\mu\text{s}$	t_{rr}	-	tbd	tbd	ns
Reverse recovery charge $V_R = 40\text{ V}, I_F = I_S, di_F/dt = 100\text{ A}/\mu\text{s}$	Q_{rr}	-	tbd	tbd	nC
Soft factor t_f / t_s	S	-	tbd	-	

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